

Fast, Low Noise Photodetectors for Nuclear Physics

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Program Goals

To develop high gain, low noise, compact CMOS based silicon photomultipliers as optical detectors for scintillation studies in nuclear and particle physics experiments. These sensors can be formatted as large area discrete devices, multi-element arrays, and can be fabricated to possess position sensitivity. These solid-state photomultipliers (SSPMs) will compete with PMTs as photodetectors in scintillations spectroscopy and calorimeter applications.

Motivation to Replace PMTs

PMTs possess high gain (10^6) and low noise (ENF ~ 1) but...

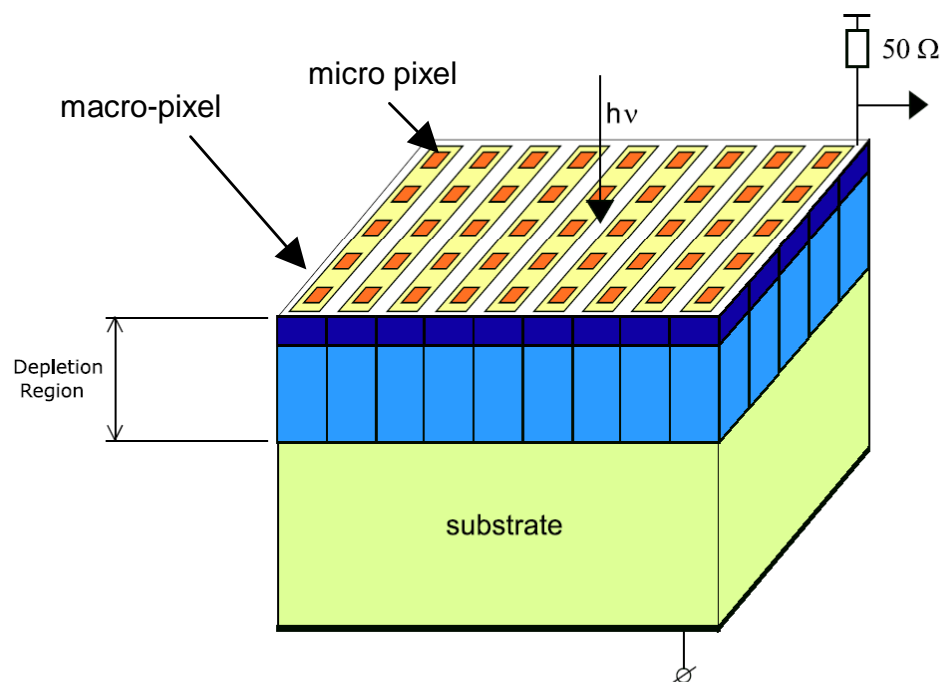
- o PMTs are bulky and fragile**
- o PMTs are sensitive to magnetic fields**
- o PMTs require high bias (~1000 V)**
- o PMTs have low quantum efficiency**
- o Spectral response of PMTs is narrow**
- o Red response of low noise PMTs is poor**

Solid-State Photomultipliers

General SSPM main features

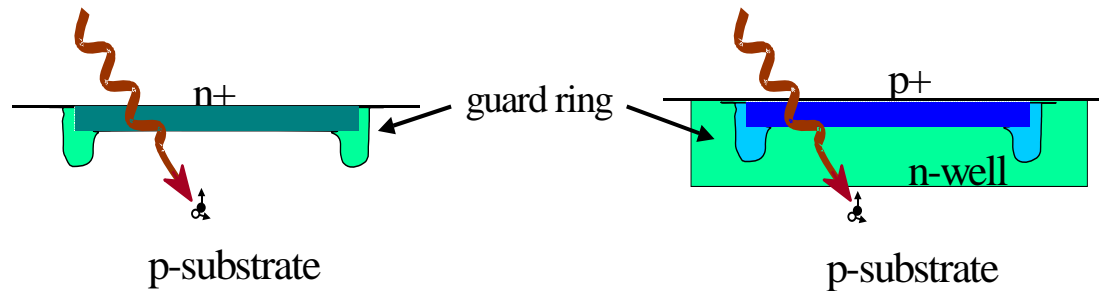
- Very high gain ($>10^5$), very simple electronic readout
- Low bias operation (~ 30 V)
- Fast response (sub-ns rise time)
- Very low excess and electronic noise (<1 electron level)
- Dark noise a problem at very low light levels
- Insensitive to magnetic fields
- Position sensitive structures possible
- RMD fabricates these devices by CMOS process, hence cost should be very low upon mass production.
- On-chip integration of readout electronics possible

MRS Silicon Photomultiplier



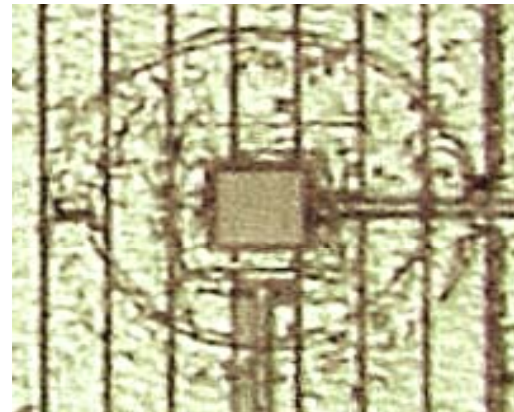
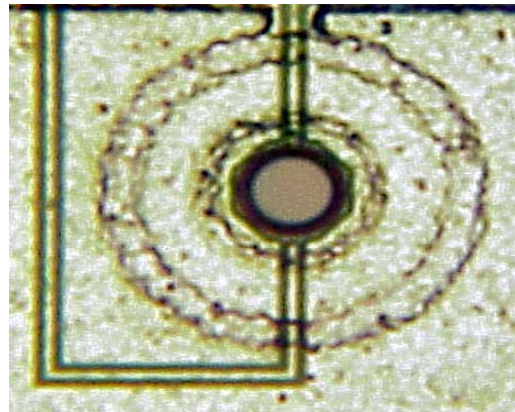
- Independent Geiger Mode Micro-APDs ($\sim 30 \mu\text{m}$)
- Binary output, constant amplitude
- Passively quenched
- Common substrate, signals are summed
- Single analogue output

CMOS SSPM Micro-Pixels

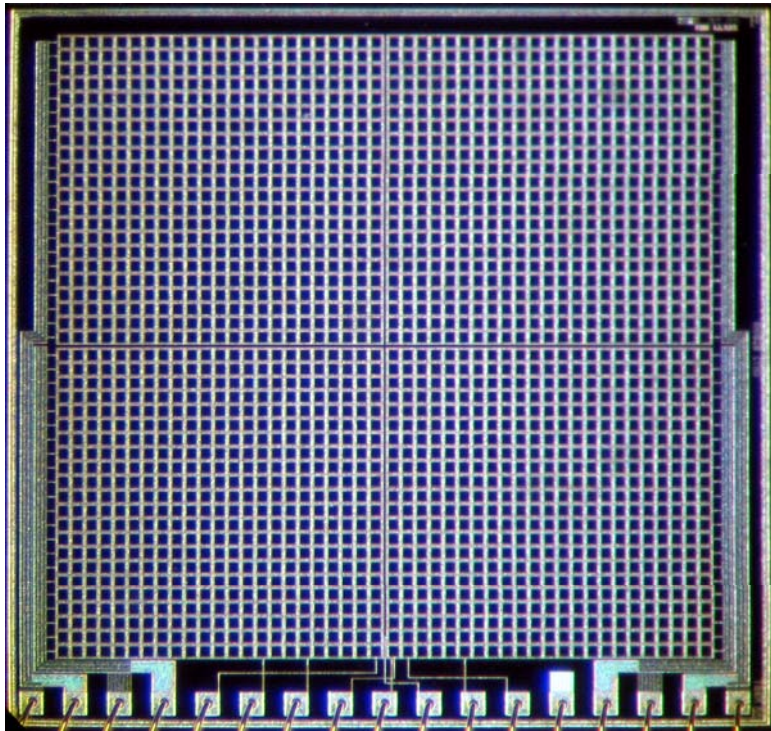


Design 1 (n-on-p) deep

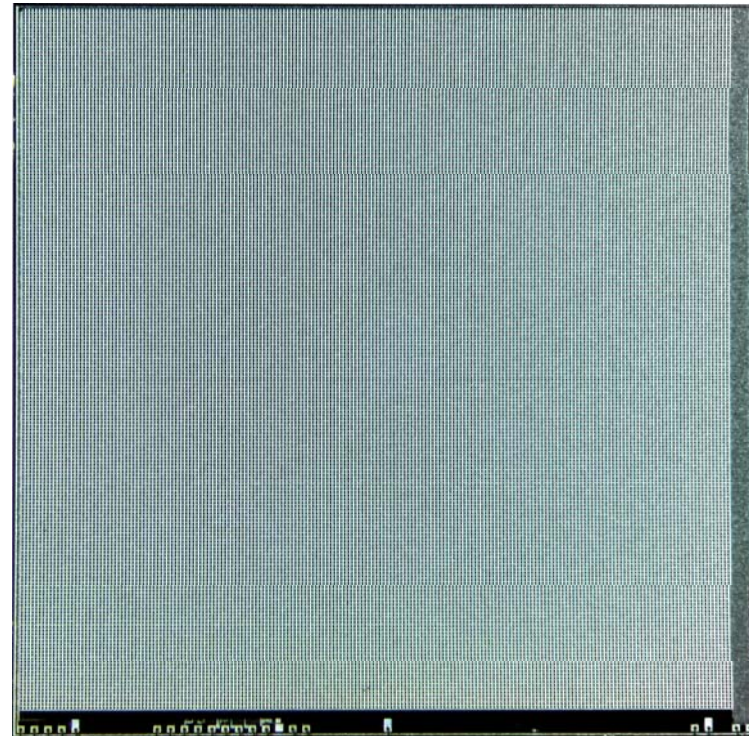
Design 2 (p-on-n) shallow, but isolated from substrate



CMOS SSPMs

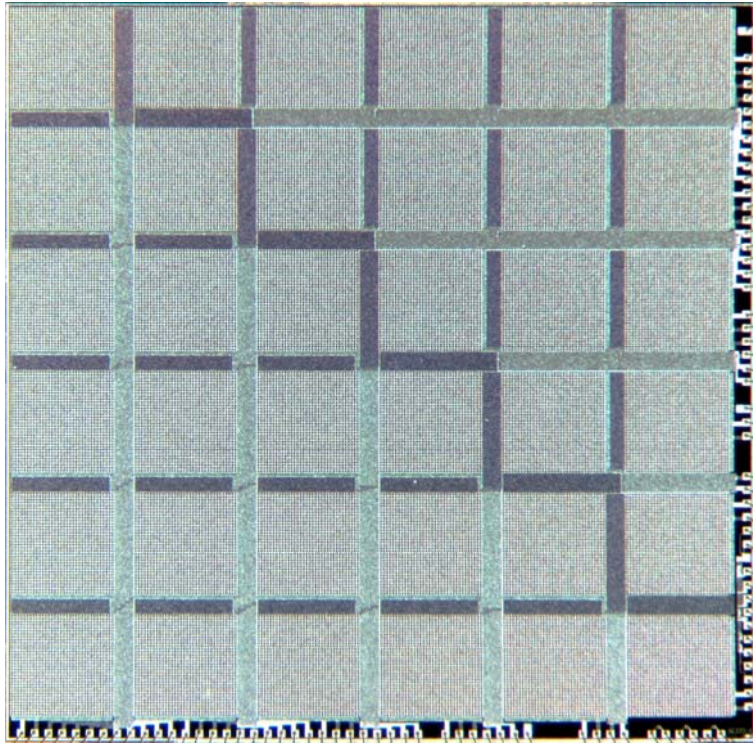


**3 x 3 mm² area
50 micron pixels
61% fill factor**

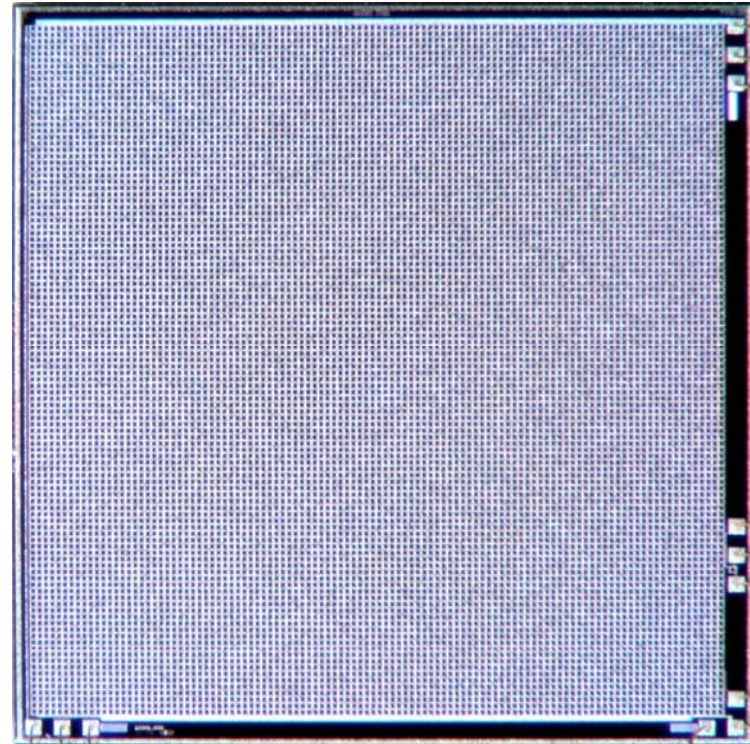


**10 x 10 mm² area
30 micron pixels
49% fill factor**

CMOS SSPMs

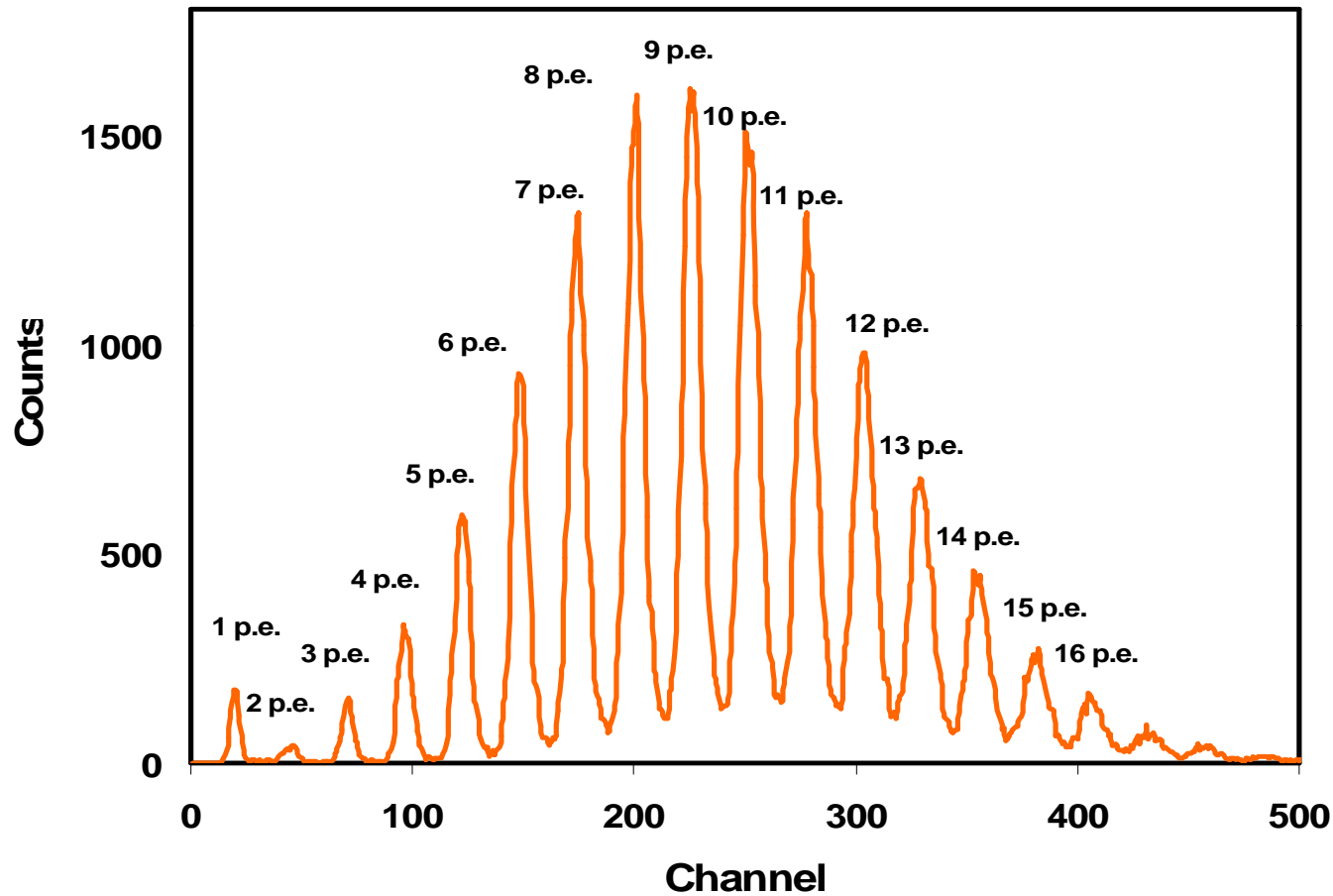


6 x 6 SSPM Array

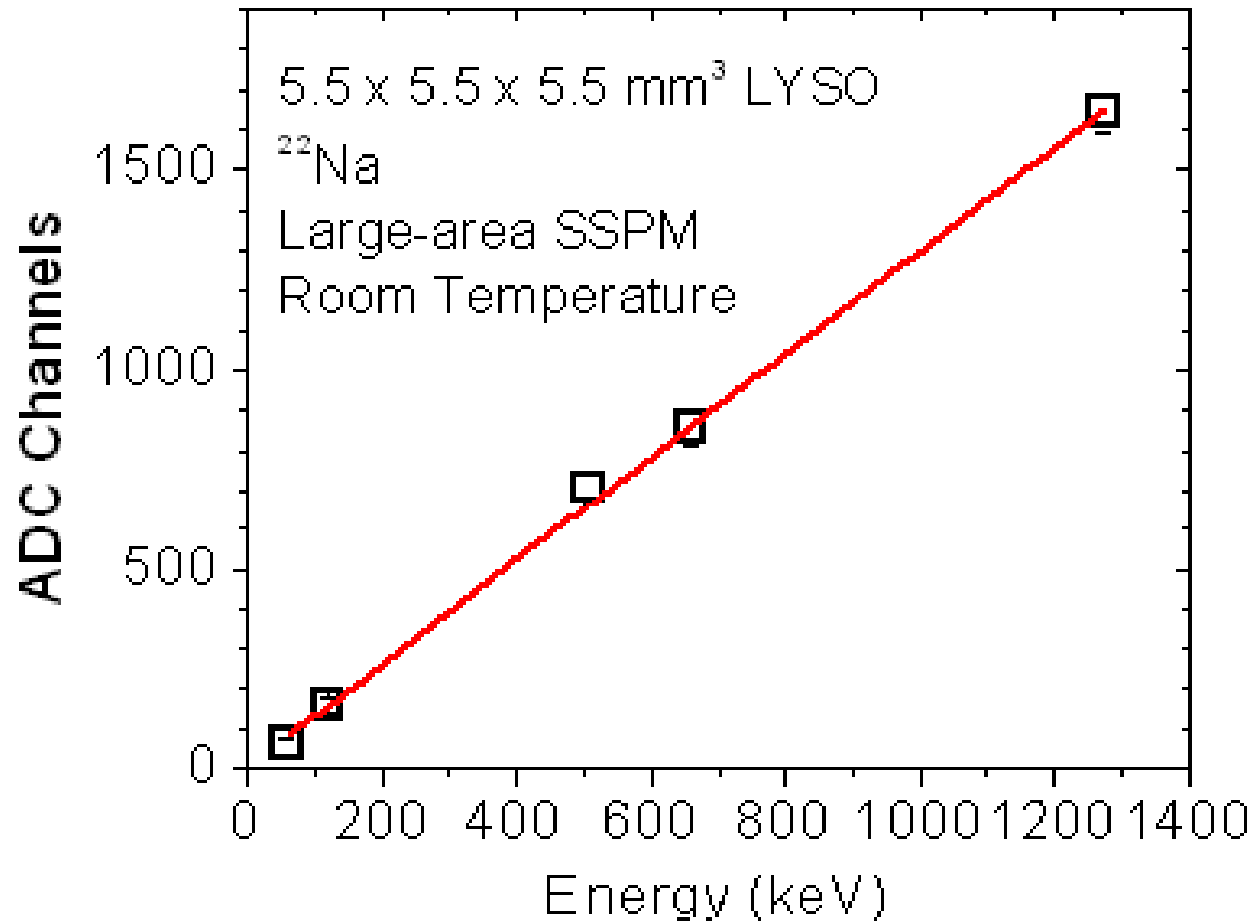


5 x 5 mm² PS-SSPM

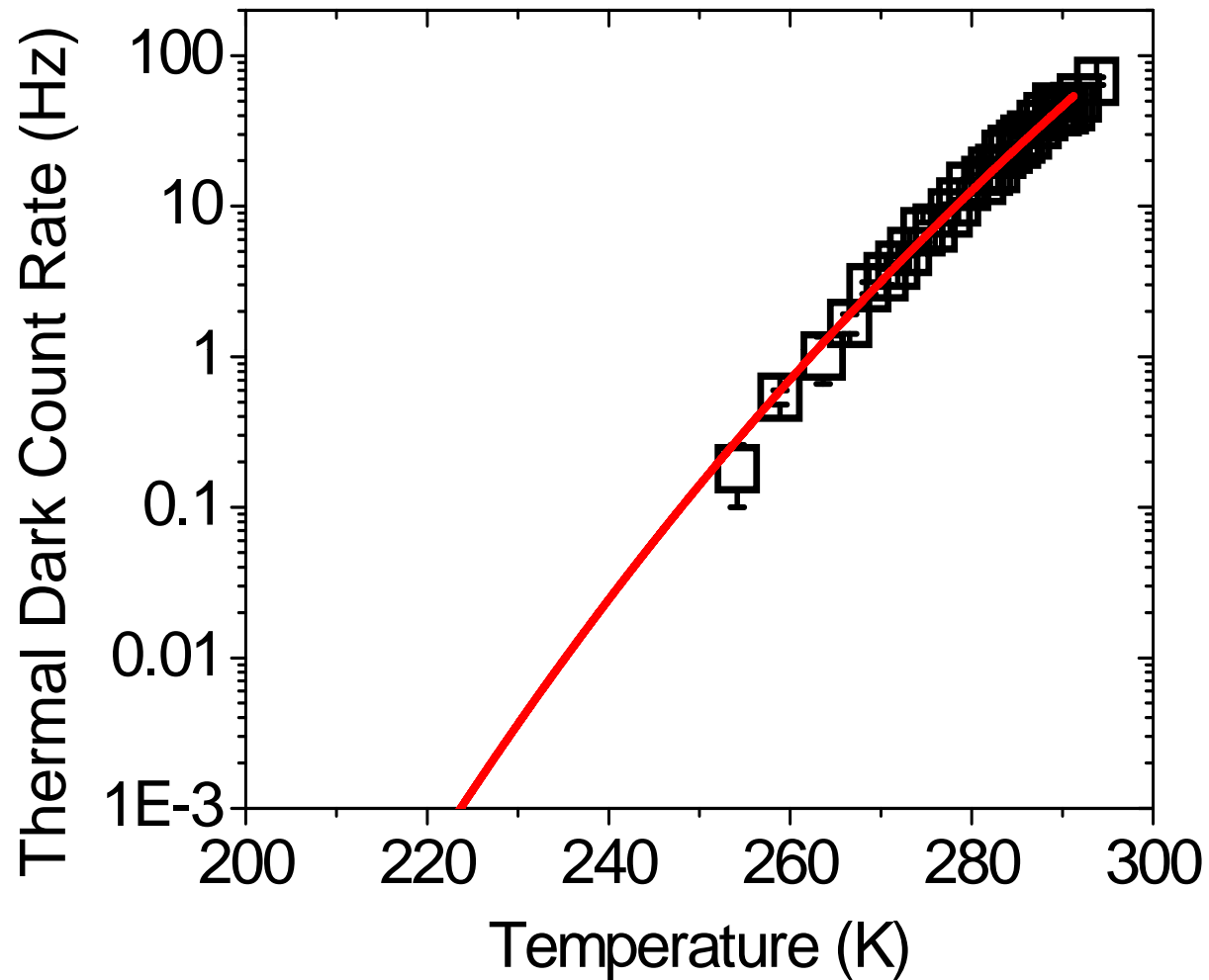
SSPM Single Photon Sensitivity



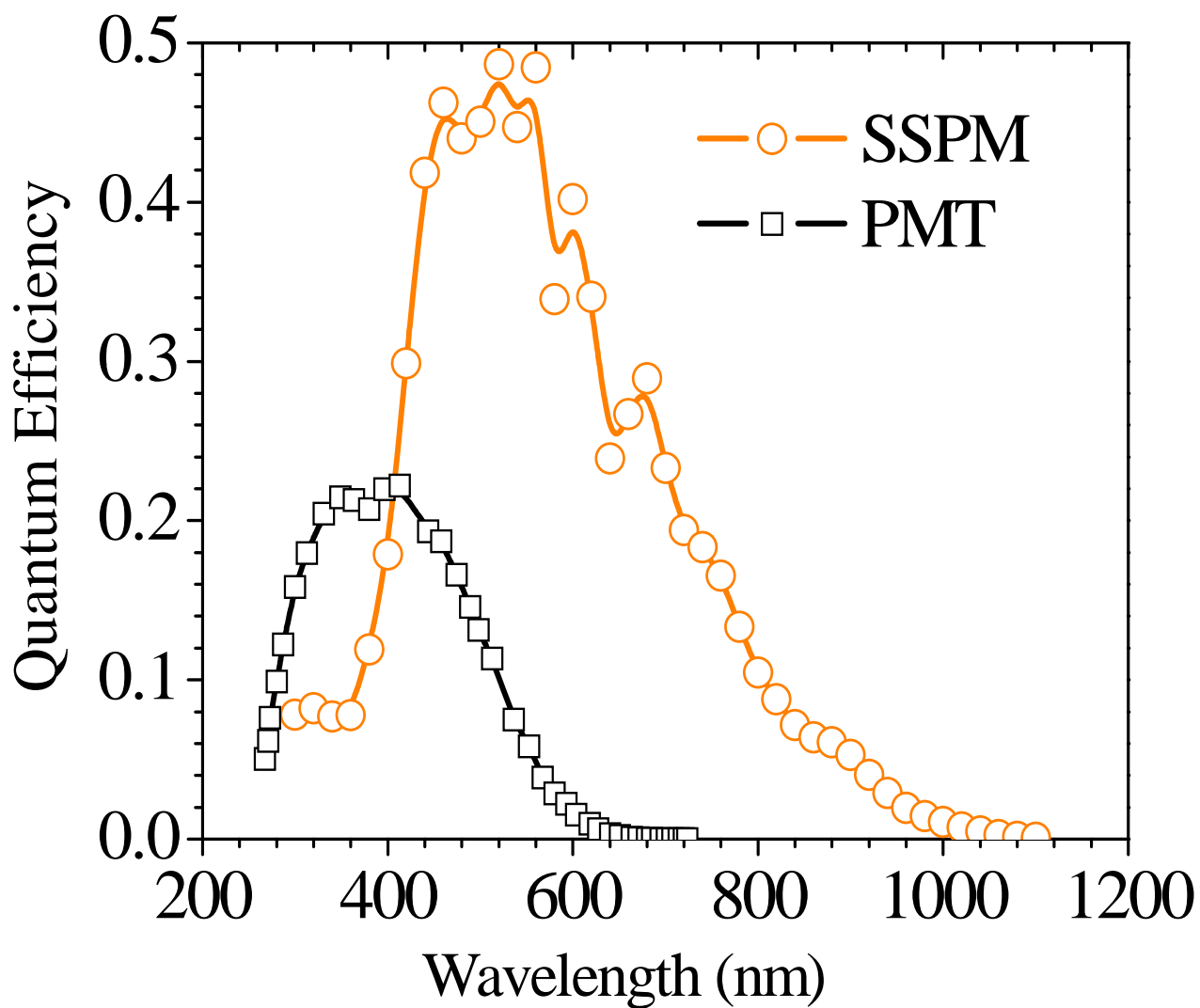
1 cm² SSPM Linearity



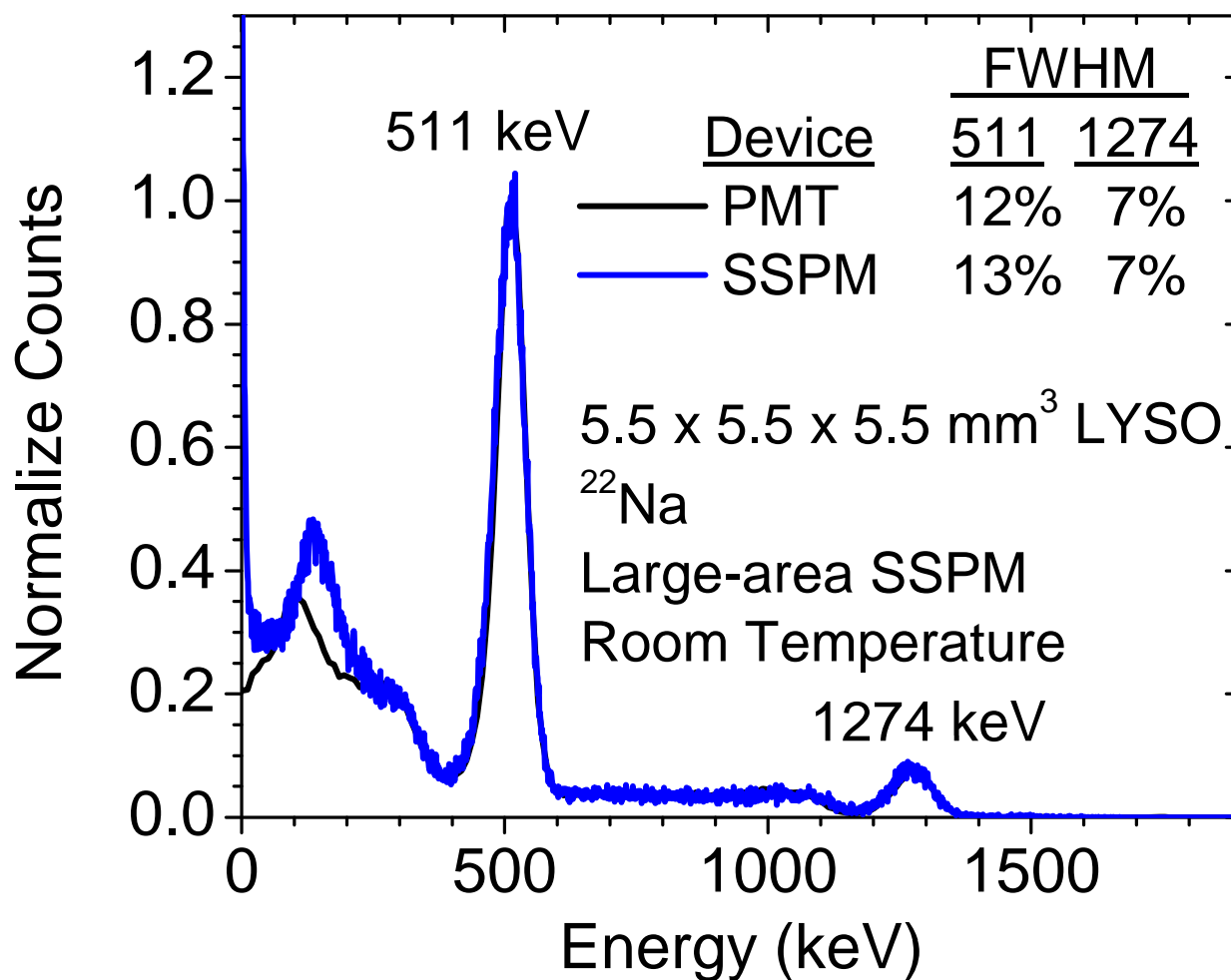
SSPM Dark Count Rate



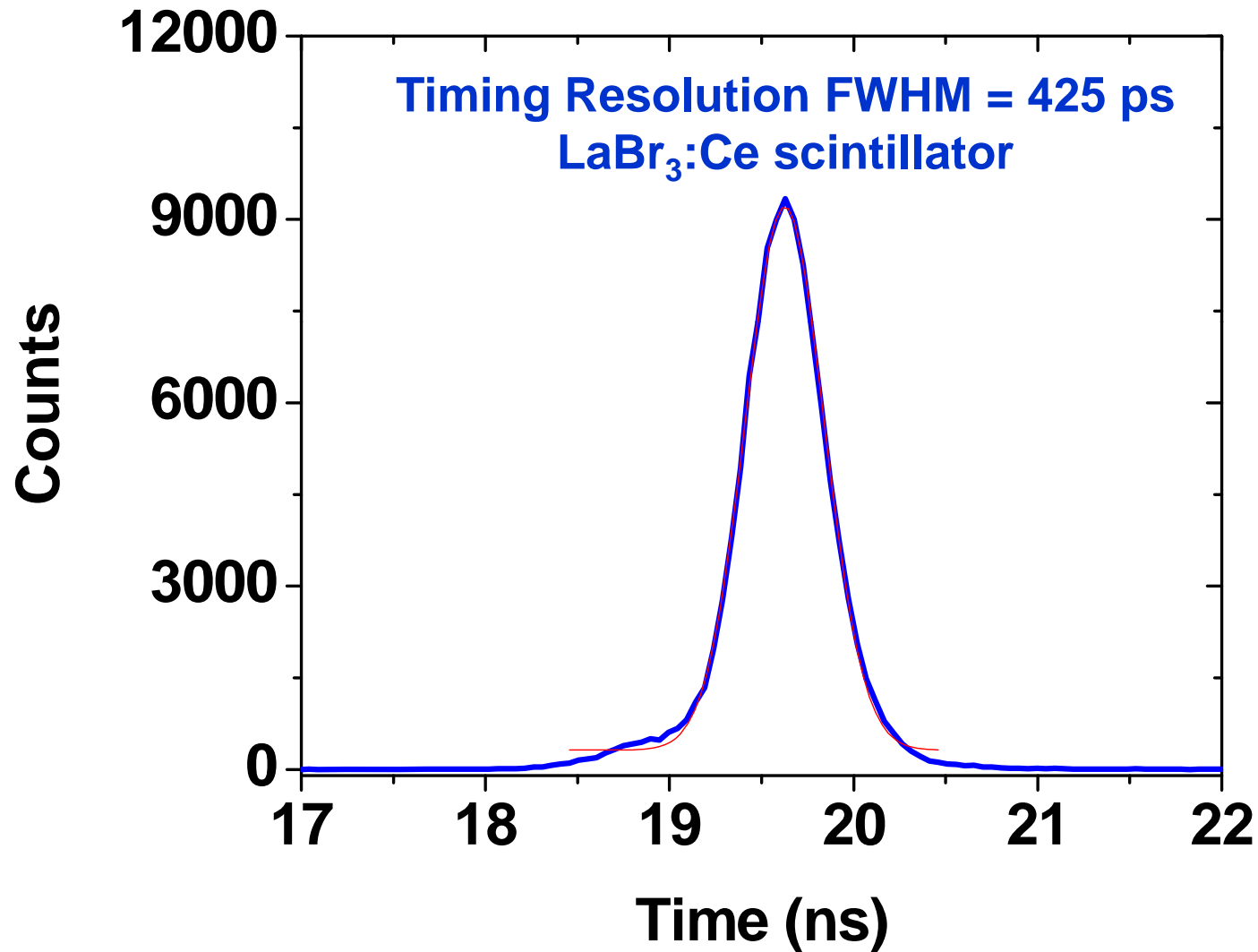
SSPM Quantum Efficiency



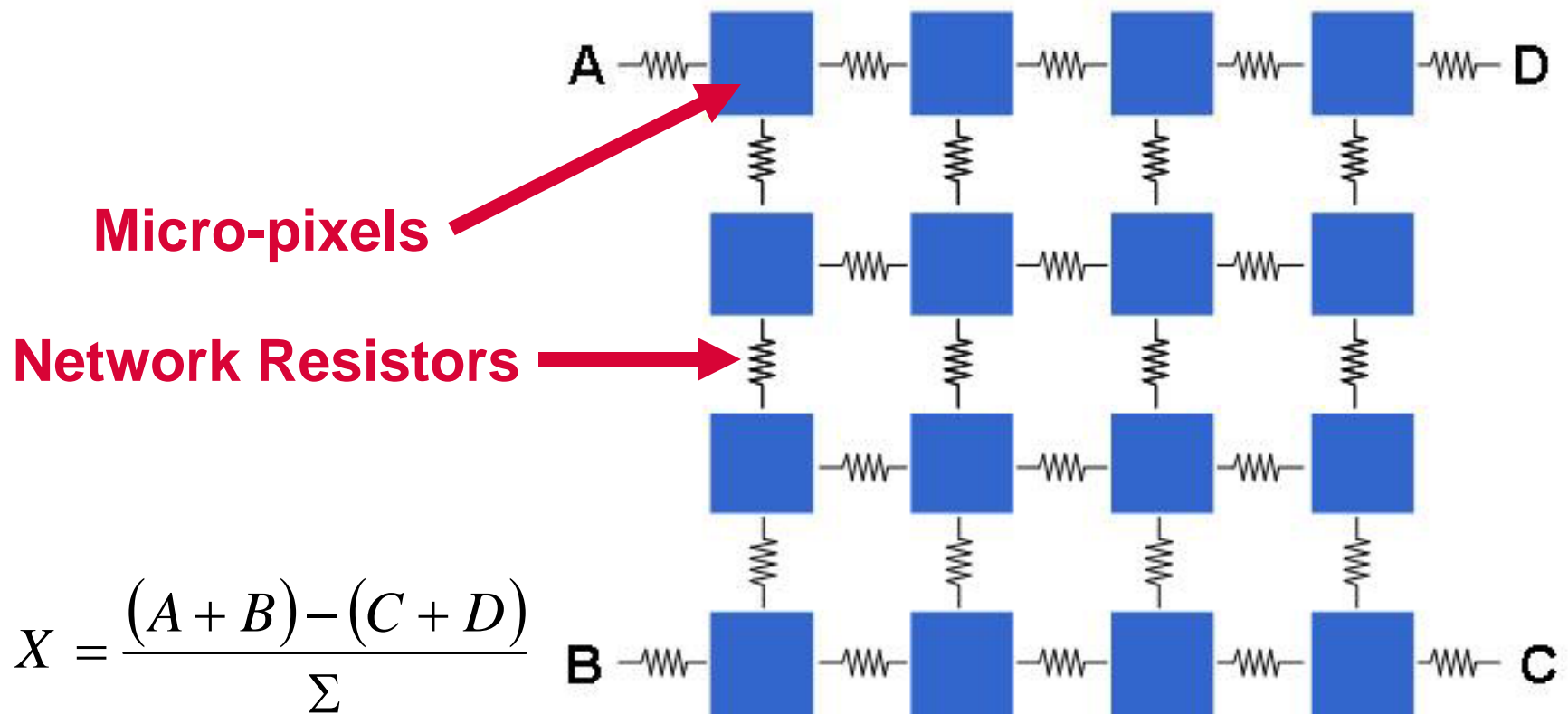
SSPM Energy Resolution



SSPM Timing Resolution



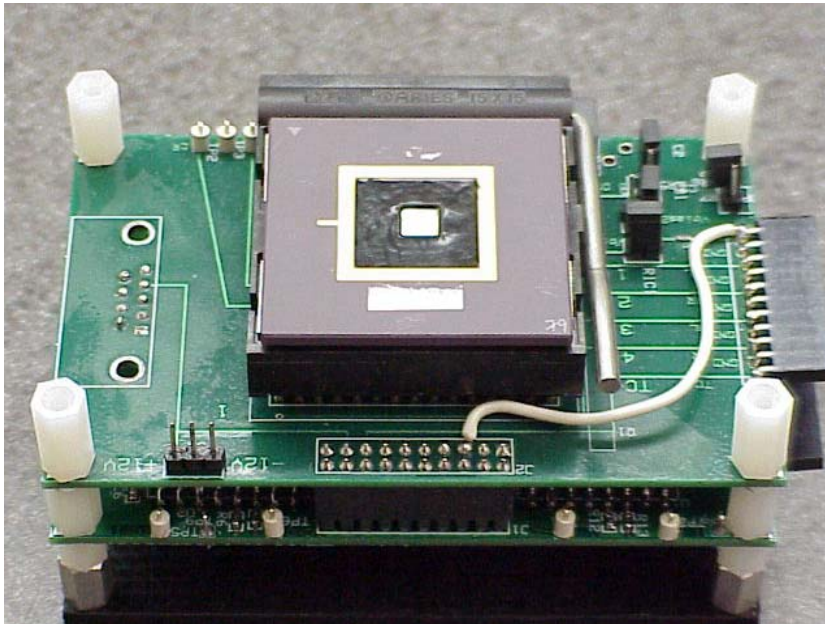
Position Sensitive SSPM Concept



$$X = \frac{(A + B) - (C + D)}{\Sigma}$$

$$Y = \frac{(A + D) - (B + C)}{\Sigma}$$

PS-SSPM & Readout PCB

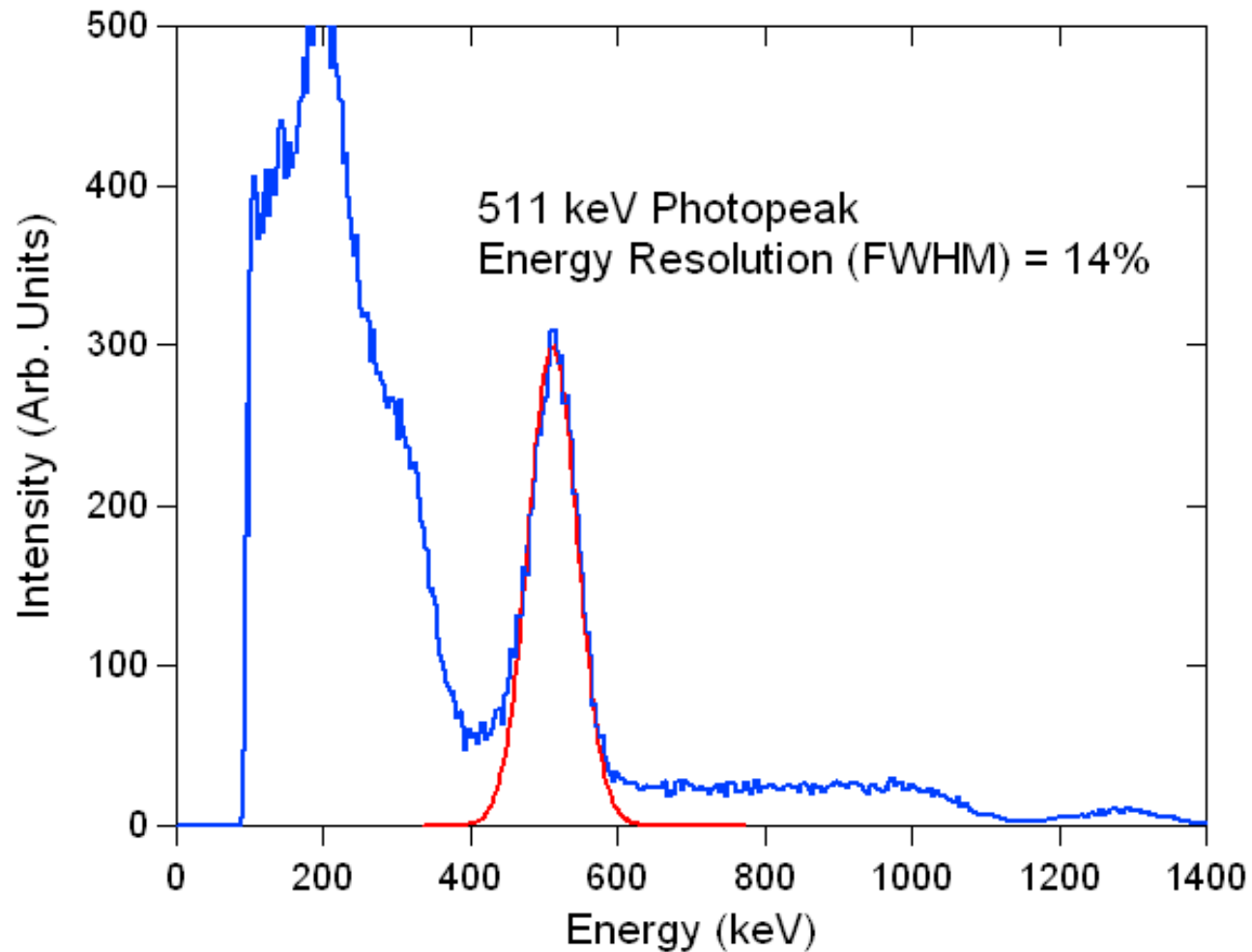


PS-SSPM Parameters

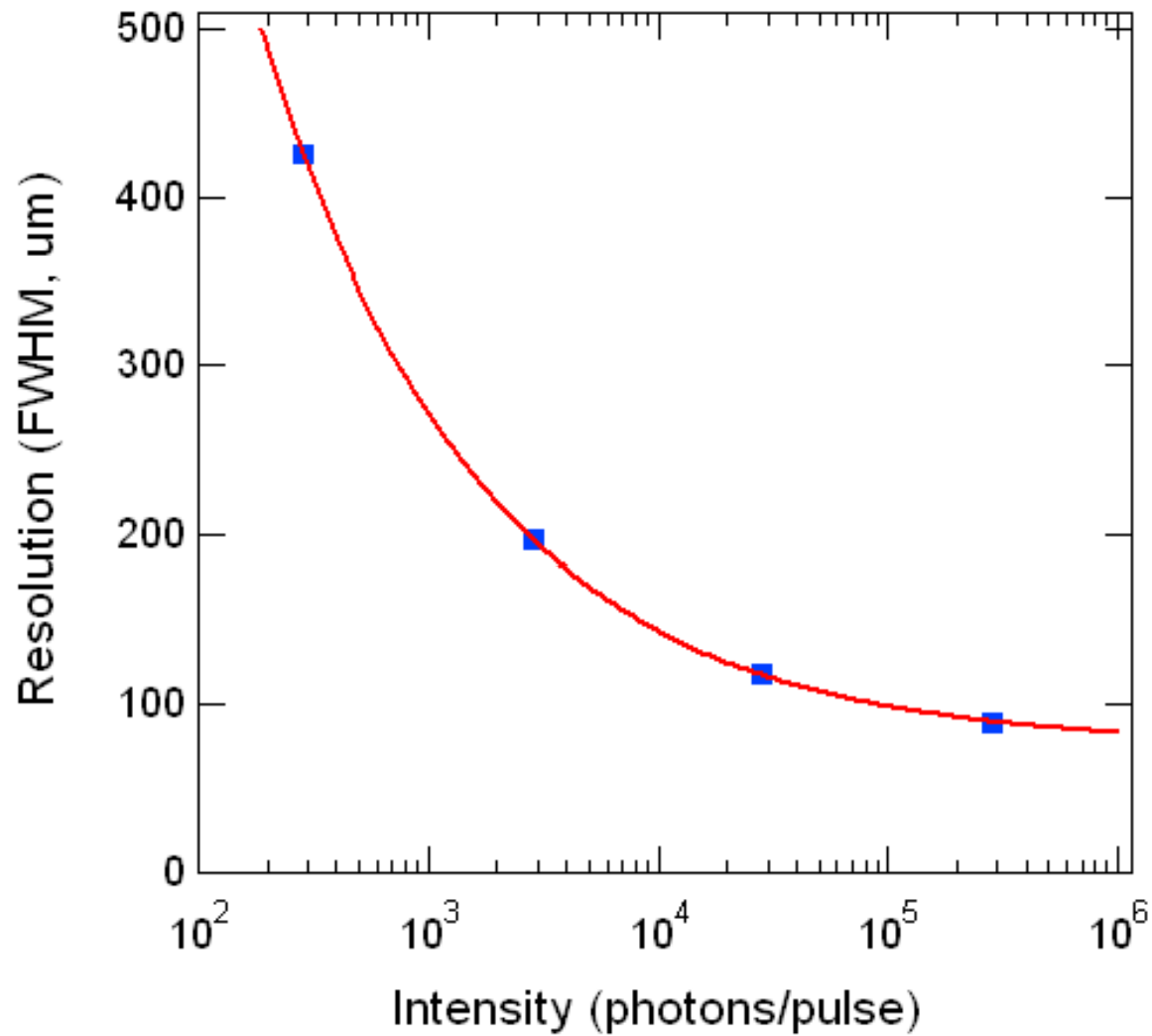
Number of micro-pixels	11,664 (108 x 108)
Micro-pixel area	30 x 30 μm^2
Micro-pixel pitch	44.3 x 44.3 μm^2
Geometrical Fill Factor	46%
Quench Resistors	143.8 k Ω
Network Resistors	246.5 Ω
Detection efficiency @ 400 nm	~ 10%
Dark Current ($\mu\text{A}/\text{mm}^2$)	10
Dark Count Rate (kHz/pixel)	~ 117
Operating Bias	~ 32 V
Operating gain	~ 10^6
Excess Noise Factor	~ 1
Capacitance (fF/pixel)	150

- PS-SSPM chip was packaged on a ceramic 145 pin grid array
- Zero insertion force (ZIF) socket for easy removal
- Custom PCB, preamplifiers located under PS-SSPM

PS-SSPM Energy Resolution



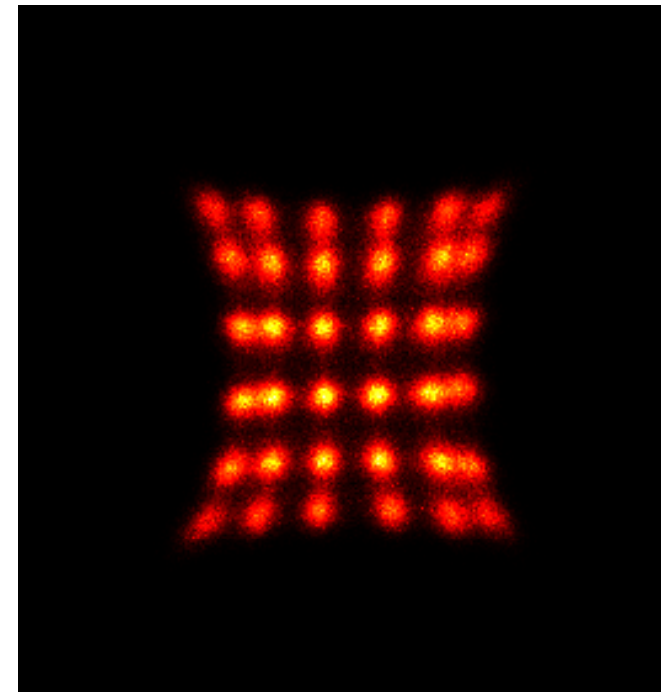
PS-SSPM Spatial Resolution



PS-SSPM Scintillator Images



6 x 6 LYSO array having
500 μm pixels

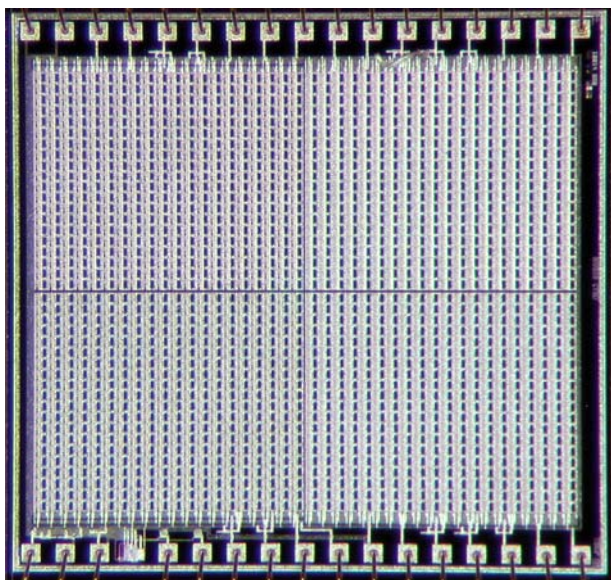


Uniform flood with ^{22}Na
(511 keV)

RMD has filed for IP on the PS-SSPM concept

Temperature-insensitive SSPM

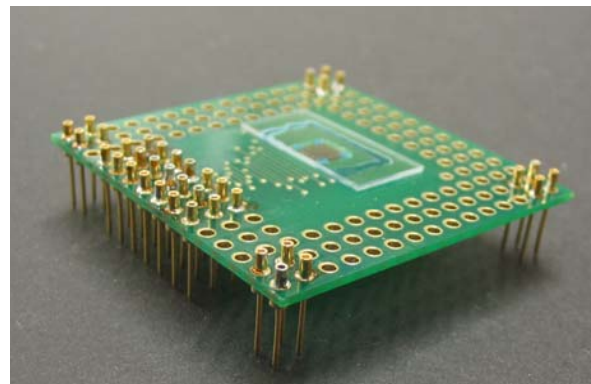
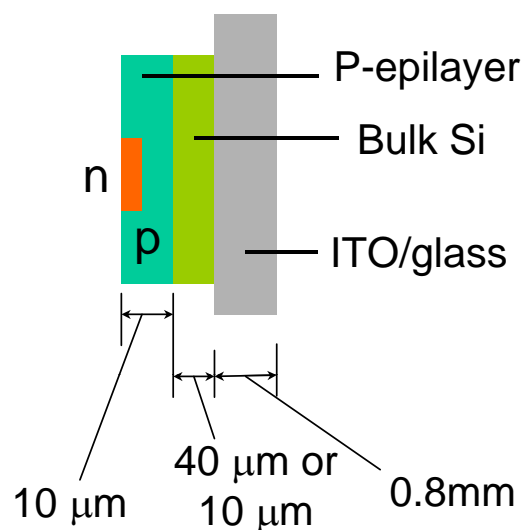
$$Q_{OUT} = DE(V_X) \times N \times C(T) \times V_X(T)$$



Excess bias affects detection efficiency and gain

- Breakdown voltage is temperature dependent.
- To maintain a constant excess bias, the applied bias must change with temperature.
- Feed isolated pixel signal from dark events into a peak-hold circuit to monitor changes in the excess bias.

Back-Illuminated SSPMs



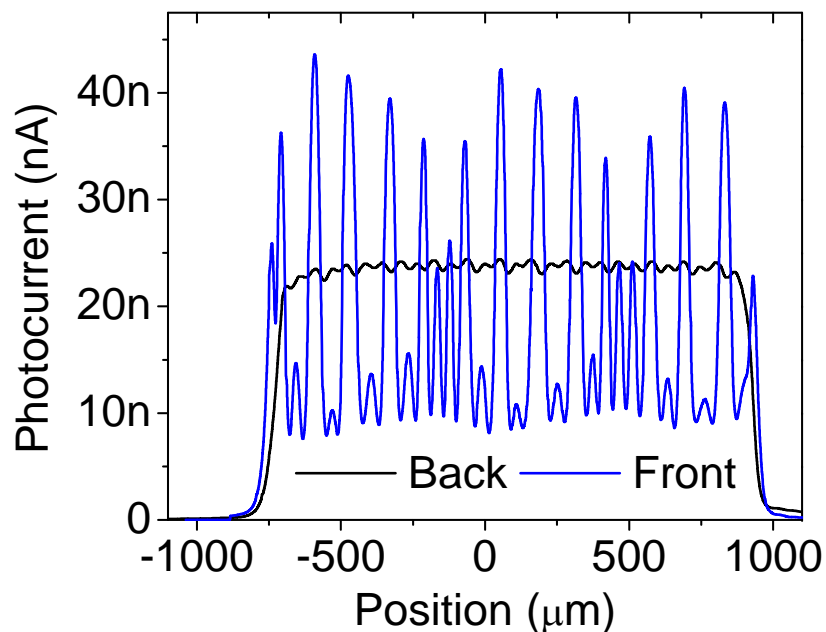
Thinned to 50 μm and 20 μm (thinner chips are in process).

Packaged for front and back illumination.

DCR same

FF ~100%, detection efficiency is currently high only in red

White light Illumination



Comparison of Photodetectors

Device	Gain	Excess Noise	QE (> 350 nm)	Voltage	Rise time	Magnetic sensitivity
SSPM	$\sim 10^6$	~ 1.3	$\sim 30\%-50\%*$	$\sim 30\text{ V}$	$\sim 0.1\text{ ns}$	No
Si APD	$\sim 10^3$	> 2	$\sim 60\%$	$> 1\text{ KV}$	1-2 ns	No
Si PIN	1	~ 1	$\sim 70\%$	$\sim 30\text{ V}$	$> 10\text{ ns}$	No
PMT	$\sim 10^6$	~ 1.2	$\sim 30\%$	$> 1\text{ KV}$	$\sim 0.1\text{ ns}$	Yes

*This value is the 'photon detection efficiency' and 50% represents the projected value based on our designs.

Future Work

- Package and characterize thinner ($\sim 10 \mu\text{m}$) back illuminated SSPMs.
- Characterize imaging and non-image 1 cm^2 SSPM
- Develop on-chip electronics for pixel conditioning, pulse processing, and data management.
- Characterizing 6×6 SSPM array
- Deploy SSPM detectors for integration into nuclear and particle physics experiments running at BNL (calorimetry) and UMass-Lowell (beam monitoring in particle accelerators, α - γ angular correlations and charged particle detection).